Special Issue

Single-Event Effects: Modeling, Prediction, Testing and Radiation Hardening

Message from the Guest Editors

SEEs will be explored across a wide range of applications and technology platforms, from traditional **space systems** to emerging **ground-level environments,** like autonomous vehicles, high-performance computing, medical devices, and particle accelerators. Additionally, this Special Issue will highlight new approaches in **alternative SEE testing methodologies**—using tools like lasers and high-energy heavy ions—and discuss the challenges in the **radiation monitoring and dosimetry** needs involved in ensuring accurate SEE characterization and rate prediction. The topics of interest include, but are not limited to, the following:

- Modeling and prediction of single-event effects;
- Experimental characterization of single-event effects;
- Testing methodologies;
- Radiation-hardening-by-design (RHBD) techniques;
- Radiation-hardening-by-process (RHBP) techniques;
- Single-event effects in disruptive technologies like quantum computing, silicon photonics, and AI-driven applications.

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

Editor-in-Chief

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